



US00D644258S

(12) **United States Design Patent**  
**Noda et al.**

(10) **Patent No.:** **US D644,258 S**

(45) **Date of Patent:** **\*\* Aug. 30, 2011**

(54) **ELECTRON MICROSCOPE**

(75) Inventors: **Hiroyuki Noda**, Kokubunji (JP);  
**Mitsuru Oonuma**, Tokyo (JP); **Akira Omachi**, Komae (JP); **Masahiro Nemoto**, Hitachiota (JP); **Kiyoshi Sasagawa**, Honjo (JP)

(73) Assignee: **Hitachi High-Technologies Corporation**, Tokyo (JP)

(\*\*) Term: **14 Years**

(21) Appl. No.: **29/366,707**

(22) Filed: **Jul. 29, 2010**

(30) **Foreign Application Priority Data**

Feb. 22, 2010 (JP) ..... 2010-004042

(51) **LOC (9) Cl.** ..... **16-06**

(52) **U.S. Cl.** ..... **D16/131**

(58) **Field of Classification Search** ..... D16/131,  
D16/130; D24/186, 232, 216; D10/81; 250/307,  
250/310, 311, 397, 440.11; 359/383, 384,  
359/385, 389, 390, 368, 370, 371, 372, 363,  
359/388

See application file for complete search history.

(56) **References Cited**

**U.S. PATENT DOCUMENTS**

2,424,791 A \* 7/1947 Bachman et al. .... 250/311  
D173,282 S \* 10/1954 Pike ..... D16/131  
D223,669 S \* 5/1972 Nishino ..... D16/131  
D229,581 S \* 12/1973 Armbruster et al. .... D16/131  
3,814,356 A \* 6/1974 Coleman et al. .... 248/636  
3,835,320 A \* 9/1974 Helwig ..... 250/311  
D233,610 S \* 11/1974 Fossella et al. .... D13/101  
4,523,094 A \* 6/1985 Rossow ..... 250/311  
4,573,772 A \* 3/1986 Endo et al. .... 359/370  
D303,267 S \* 9/1989 Takahashi et al. .... D16/131

D332,616 S \* 1/1993 Hashimoto et al. .... D16/131  
5,350,921 A \* 9/1994 Aoyama et al. .... 250/311  
D381,031 S \* 7/1997 Miyata et al. .... D16/131  
5,864,138 A \* 1/1999 Miyata et al. .... 250/311  
5,946,131 A \* 8/1999 Wells et al. .... 359/350  
6,084,239 A \* 7/2000 Miyata et al. .... 250/440.11  
7,046,437 B2 \* 5/2006 Karaki et al. .... 359/383  
D608,810 S \* 1/2010 Stoiakine ..... D16/131  
D623,211 S \* 9/2010 Oonuma et al. .... D16/131  
D625,749 S \* 10/2010 Oonuma et al. .... D16/131  
D626,579 S \* 11/2010 Oonuma et al. .... D16/131  
D632,323 S \* 2/2011 Oonuma et al. .... D16/131  
D633,537 S \* 3/2011 Oonuma et al. .... D16/131  
D633,538 S \* 3/2011 Oonuma et al. .... D16/131  
D636,005 S \* 4/2011 Oonuma et al. .... D16/131  
D638,046 S \* 5/2011 Noda et al. .... D16/131

**FOREIGN PATENT DOCUMENTS**

JP D973373-2 2/1997  
JP D1233767 3/2005

\* cited by examiner

*Primary Examiner* — Paula Greene

(74) *Attorney, Agent, or Firm* — Antonelli, Terry, Stout & Kraus, LLP.

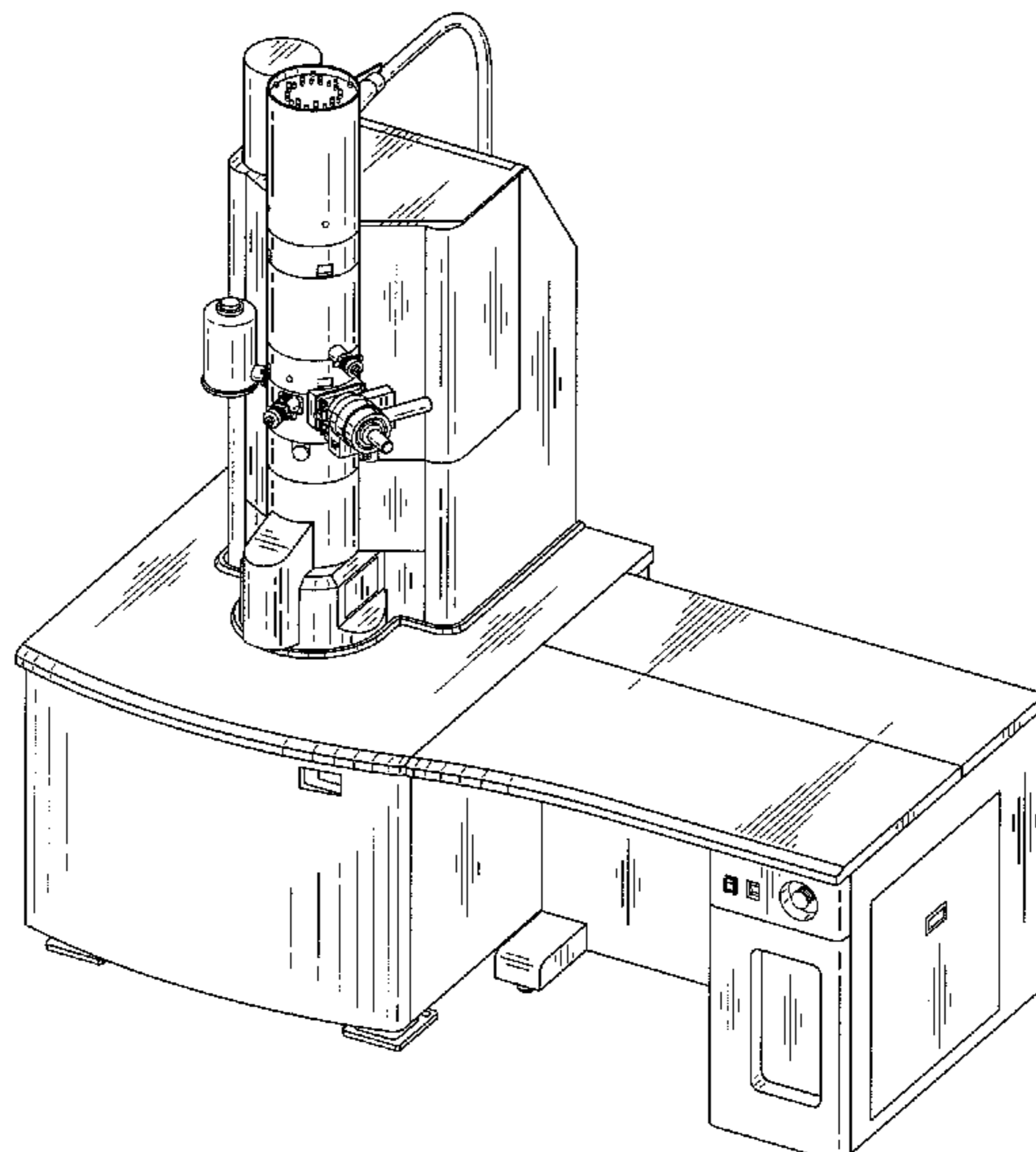
(57) **CLAIM**

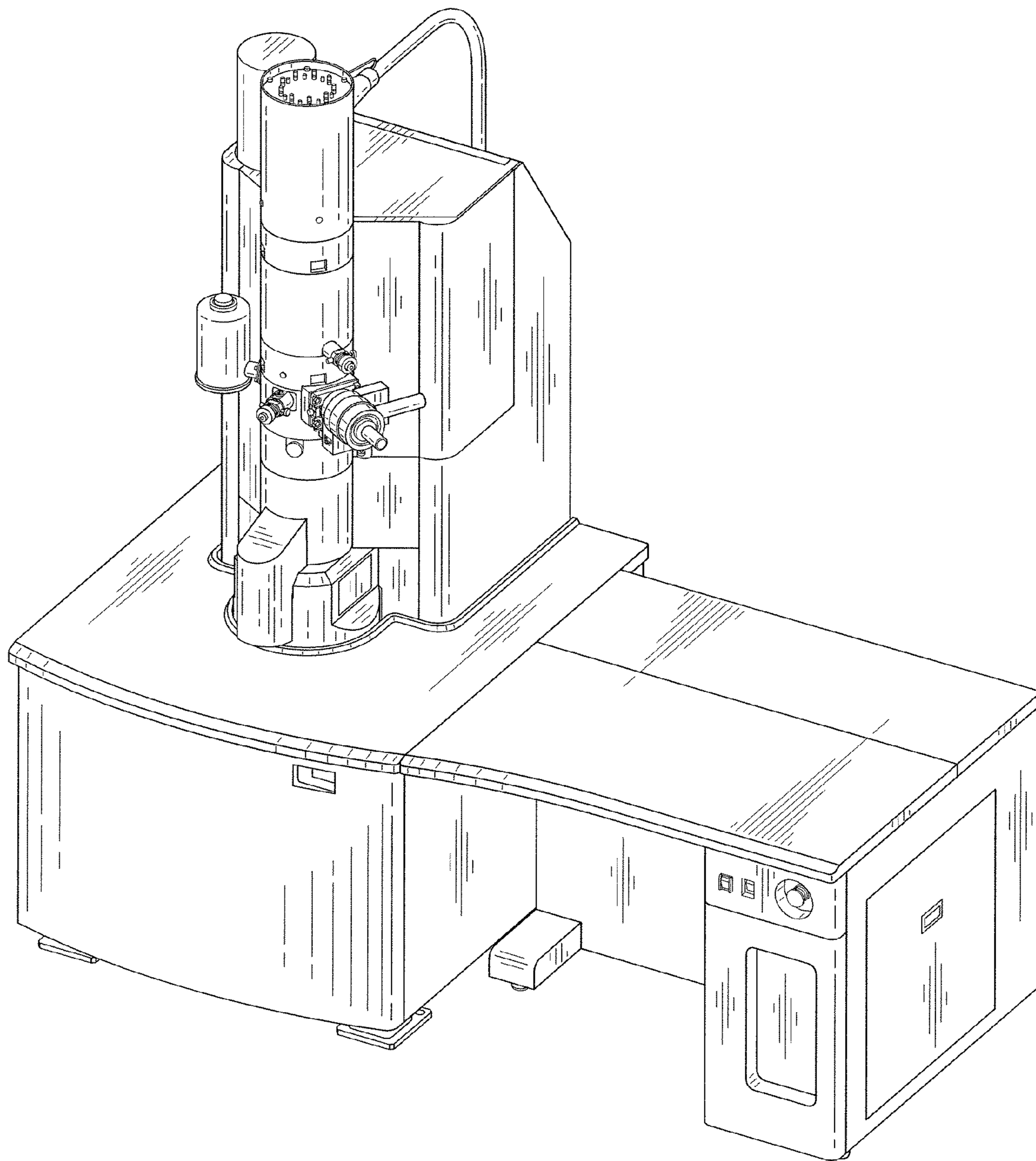
We claim the ornamental design for an electron microscope, as shown and described.

**DESCRIPTION**

FIG. 1 is a front, top and right side perspective view of an electron microscope showing our new design;  
FIG. 2 is a front elevational view thereof;  
FIG. 3 is a rear elevational view thereof;  
FIG. 4 is a top plan view thereof;  
FIG. 5 is a bottom plan view thereof;  
FIG. 6 is a left side elevational view thereof; and,  
FIG. 7 is a right side elevational view thereof.  
The broken lines shown are for illustrative purposes only and form no part of the claimed design.

**1 Claim, 7 Drawing Sheets**





**FIG. 1**

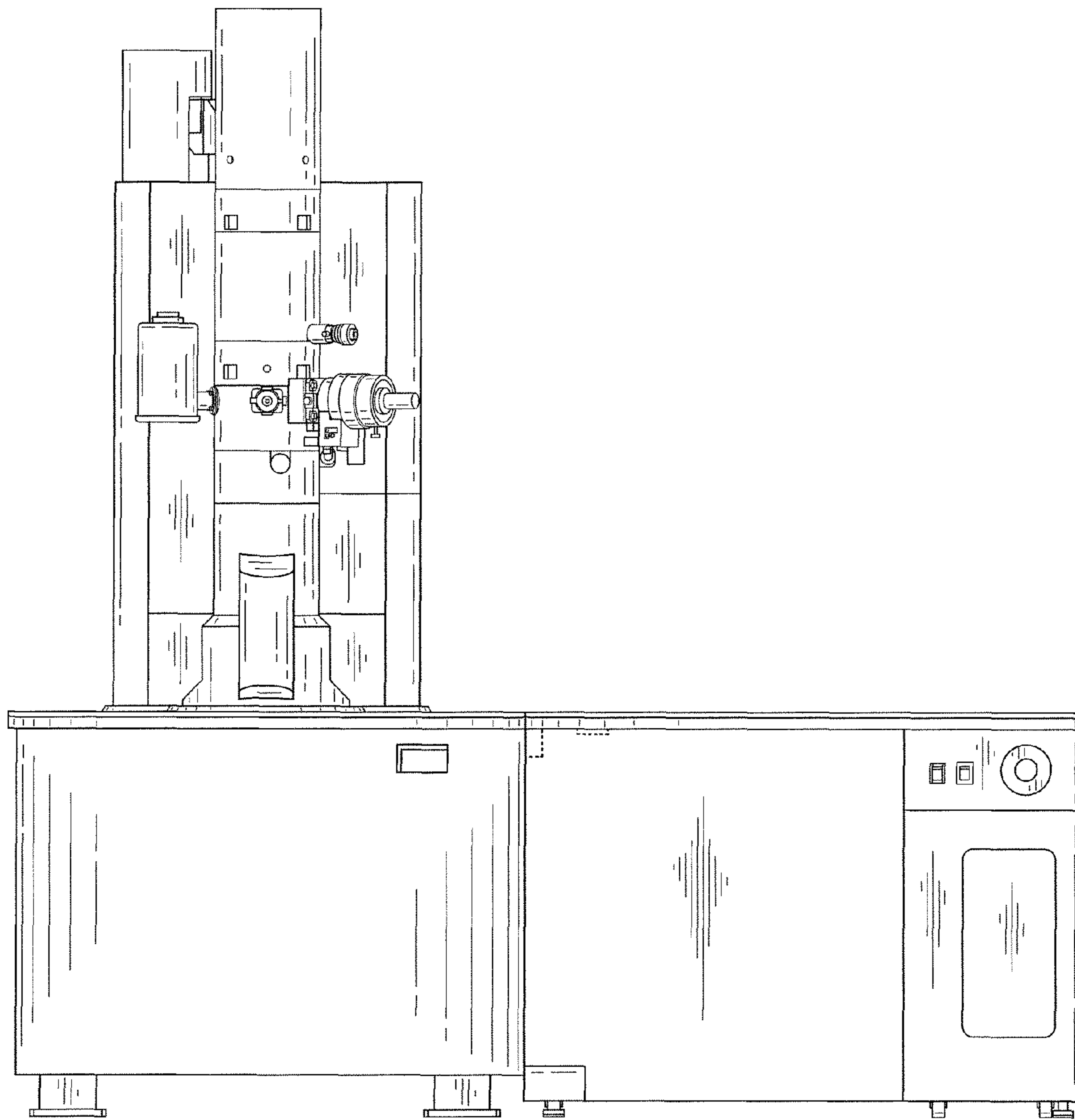


FIG. 2

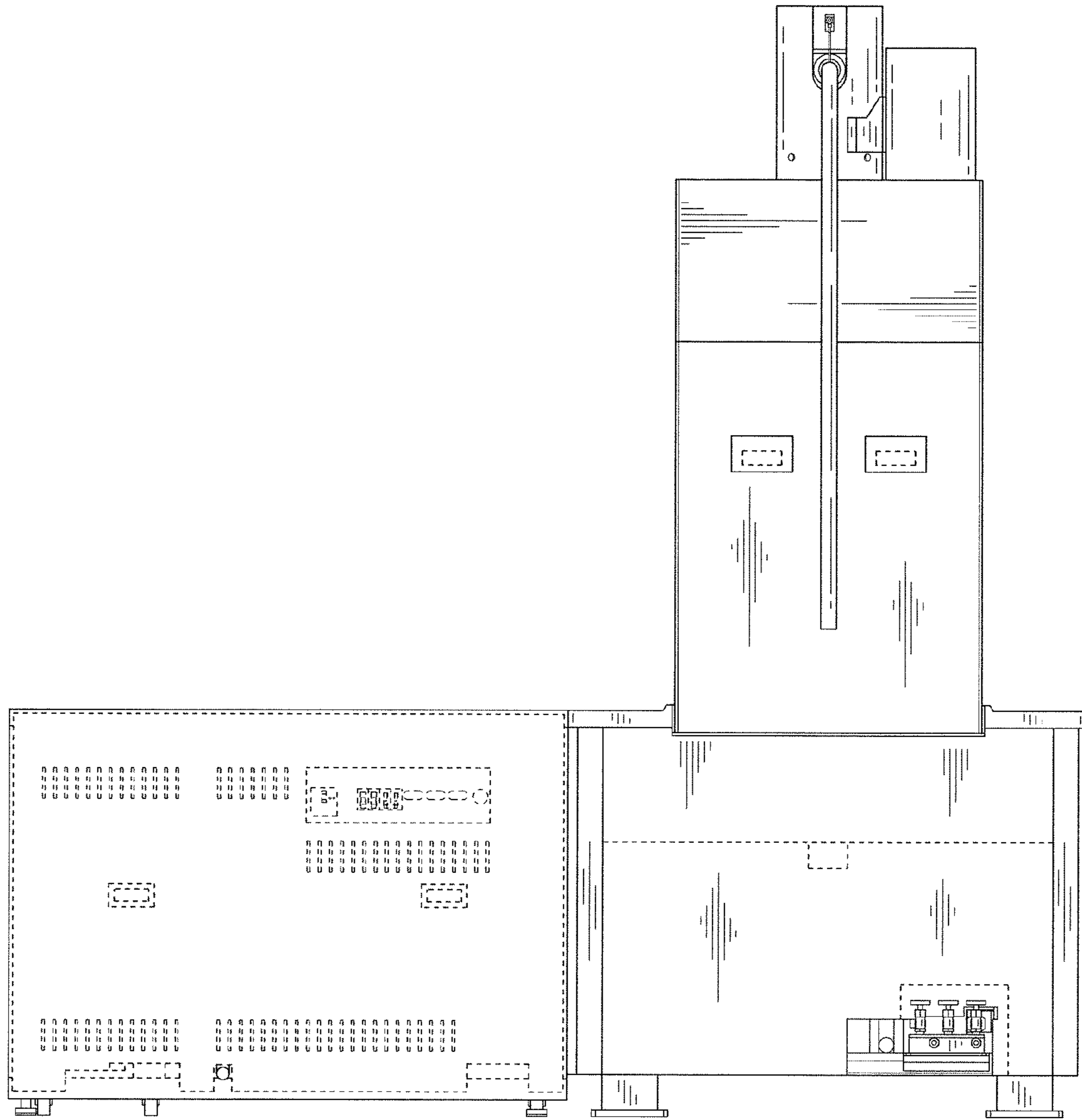


FIG. 3

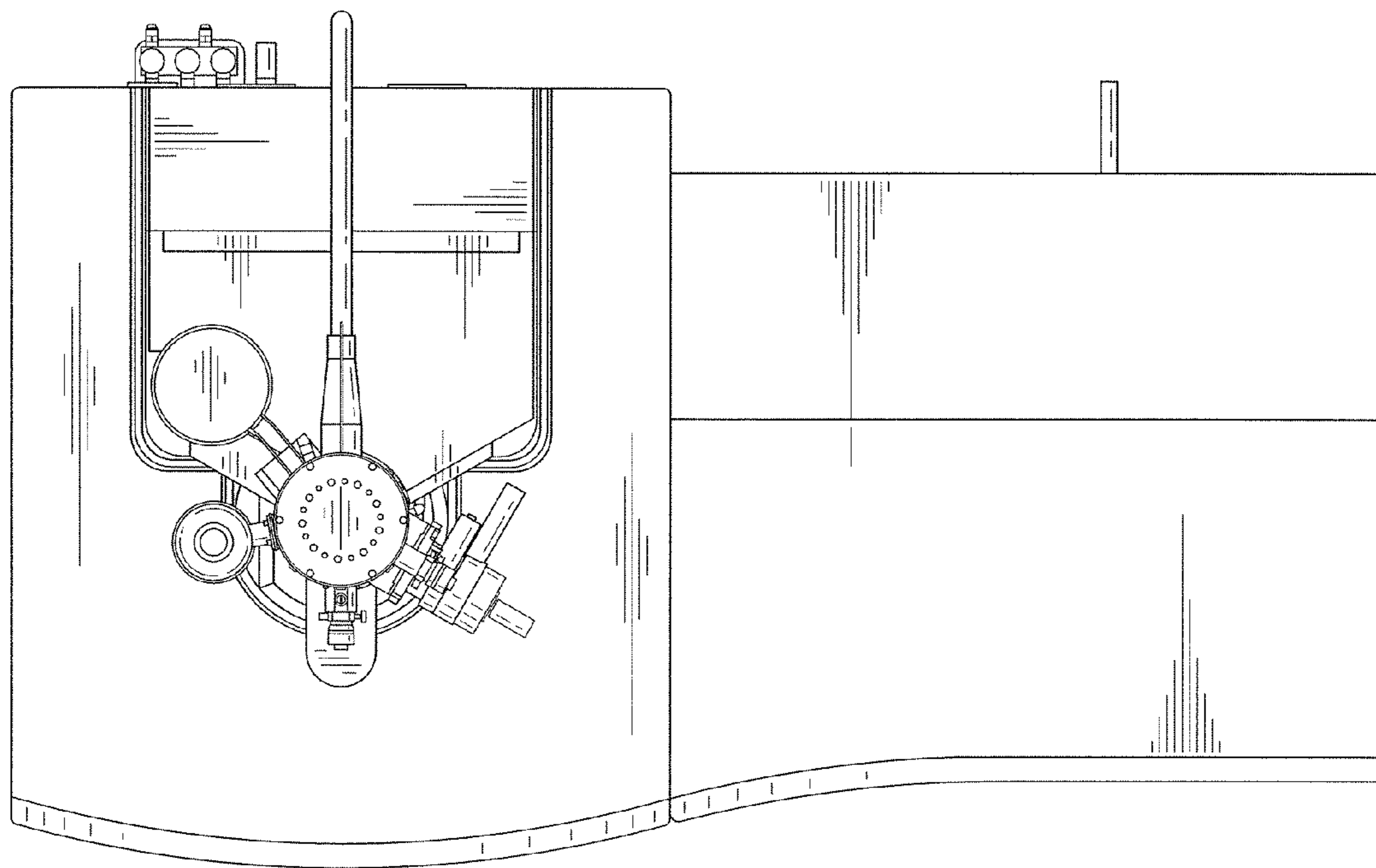


FIG. 4

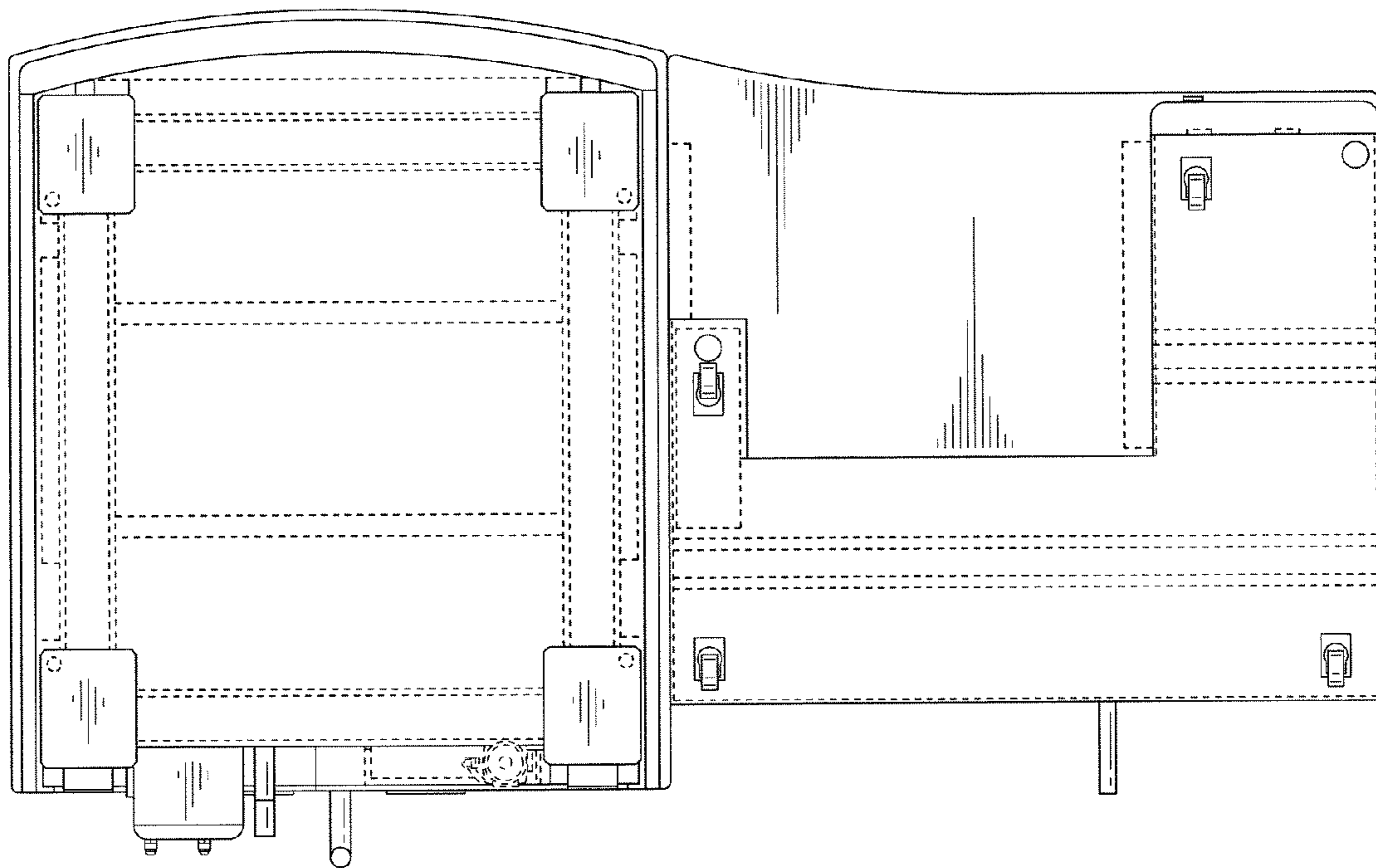
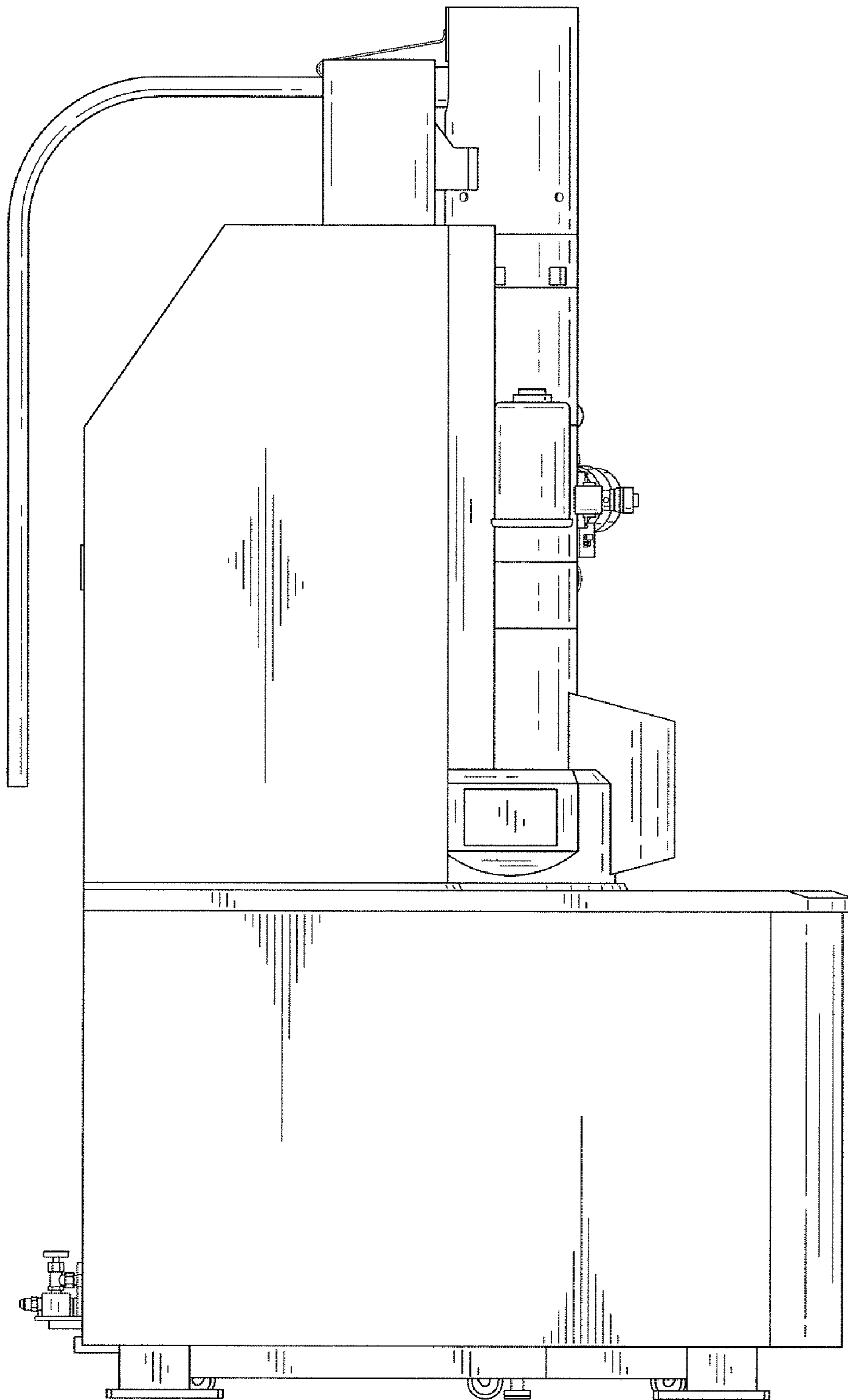
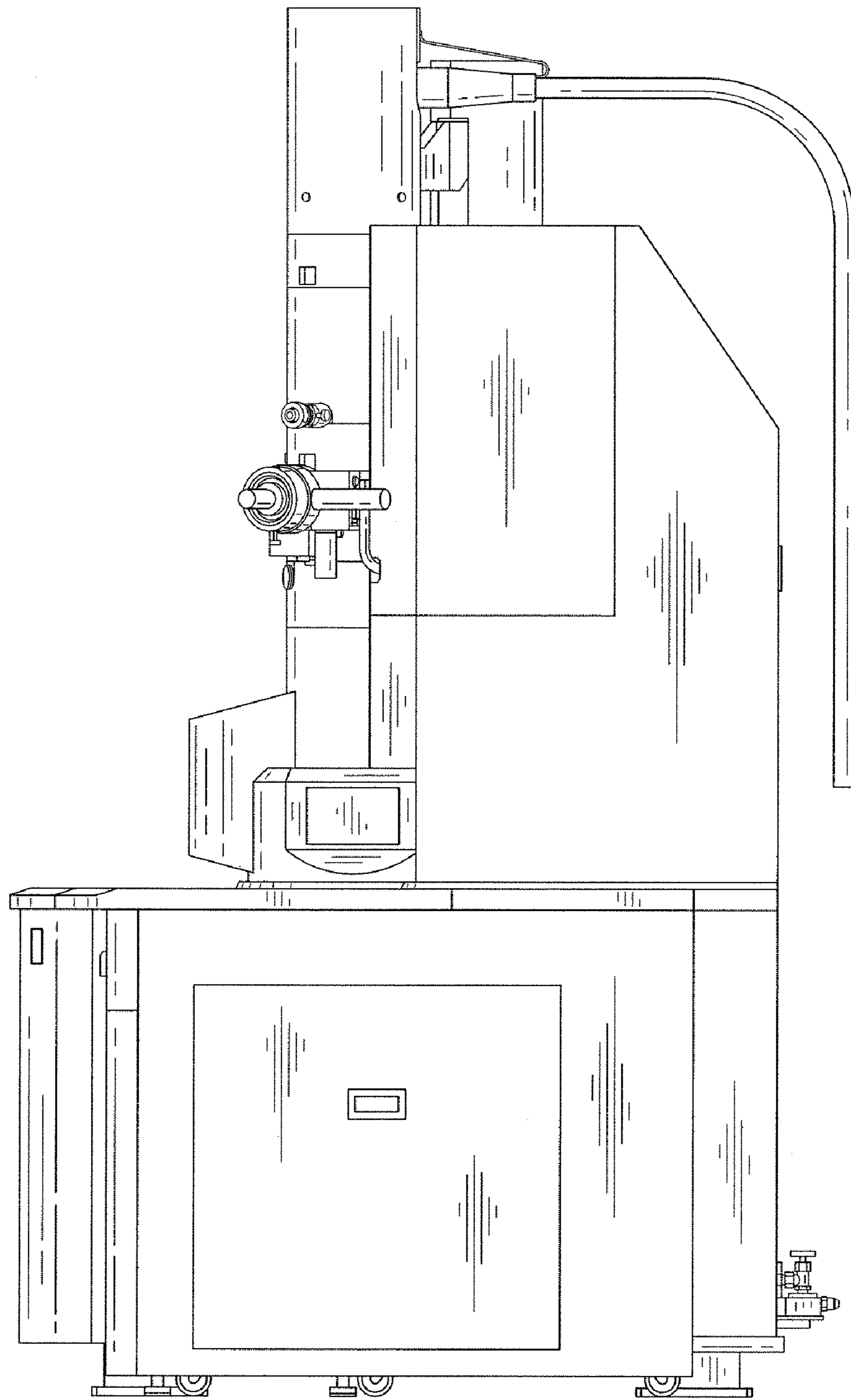


FIG. 5



**FIG. 6**



**FIG. 7**